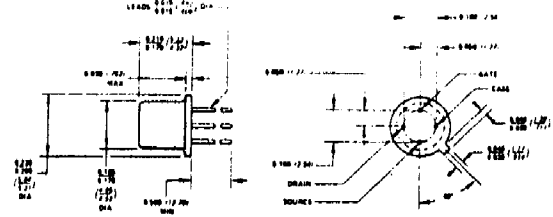


N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

FOR VERY LOW INPUT CURRENT DC AMPLIFIERS

- $I_{GSS} < 1 \text{ pA}$  (2N4117A Series)
- $I_{GSS} < 10 \text{ pA}$  (2N4117 Series)



PRODUCT CONDITIONING

Units receive the following treatment before final electrical tests:

High Temp Storage: 24 Hours at 150°C    25,000g Acceleration/Impact in the Y<sub>1</sub> Plane  
Thermal Shock: +100 to 0°C for 5 Cycles    Helium and/or Gross Leak Tests for Hermeticity

\*ABSOLUTE MAXIMUM RATINGS (25°C)

Gate-Drain or Gate-Source Voltage (Note 1)..... -40 V  
Gate-Current..... 50 mA  
Total Device Dissipation (Derate 2 mW/°C to 175°C)..... 300 mW  
Storage Temperature Range..... -65 to +175°C  
Lead Temperature 1/16" from Case for 10 sec..... 255°C

\*ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

| Characteristic  | Test Conditions   | 2N4117<br>2N4117A |      | 2N4118<br>2N4118A |      | 2N4119<br>2N4119A |      | Unit            |
|---|---|-------------------|------|-------------------|------|-------------------|------|-----------------|
|   |   | Min               | Max  | Min               | Max  | Min               | Max  |                 |
| $I_{GSS}$ Gate Reverse Current<br>2N4117 Series Only        | $V_{GS} = -20 \text{ V}$ ,<br>$V_{DS} = 0$                      | 25°C              | -10  |                   | -10  |                   | -10  | pA              |
|   |   | 150°C             | -25  |                   | -25  |                   | -25  | nA              |
| $I_{GSS}$ Gate Reverse Current<br>2N4117A Series Only       | $V_{GS} = -20 \text{ V}$ ,<br>$V_{DS} = 0$                      | 25°C              | -1   |                   | -1   |                   | -1   | pA              |
|   |   | 150°C             | -2.5 |                   | -2.5 |                   | -2.5 | nA              |
| $BV_{GSS}$ Gate-Source Breakdown Voltage                    | $I_G = -1 \mu\text{A}$ , $V_{DS} = 0$                           | -40               |      | -40               |      | -40               |      | V               |
| $V_p$ Gate-Source Pinch-Off Voltage                         | $V_{DS} = 10 \text{ V}$ , $I_D = 1 \text{ nA}$                  | -0.6              | -1.8 | -1                | -3   | -2                | -6   | V               |
| $I_{DSS}$ Drain Current at<br>Zero Gate Voltage (Note 2)    | $V_{DS} = 10 \text{ V}$ , $V_{GS} = 0$                          | 0.03              | 0.09 | 0.08              | 0.24 | 0.20              | 0.60 | mA              |
| $g_{fs}$ Common-Source<br>Forward Transconductance (Note 2) | $V_{DS} = 10 \text{ V}$ , $V_{GS} = 0$ ,<br>$f = 1 \text{ kHz}$ | 70                | 210  | 80                | 250  | 100               | 330  | $\mu\text{mho}$ |
| $g_{oss}$ Common-Source<br>Output Conductance               | $V_{DS} = 10 \text{ V}$ , $V_{GS} = 0$ ,<br>$f = 1 \text{ kHz}$ |                   | 3    |                   | 5    |                   | 10   | $\mu\text{mho}$ |
| $C_{iss}$ Common-Source<br>Input Capacitance                | $V_{DS} = 10 \text{ V}$ , $V_{GS} = 0$ ,<br>$f = 1 \text{ MHz}$ |                   | 3    |                   | 3    |                   | 3    | pF              |
| $C_{rss}$ Common-Source<br>Reverse Transfer Capacitance     | $V_{DS} = 10 \text{ V}$ , $V_{GS} = 0$ ,<br>$f = 1 \text{ MHz}$ |                   | 1.5  |                   | 1.5  |                   | 1.5  | pF              |

NOTES:

1. Due to symmetrical geometry, these units may be operated with source and drain leads interchanged.
  2. This parameter is measured during a 2 ms interval 100 ms after power is applied. (Not a JEDEC condition.)
- \*JEDEC registered data.

